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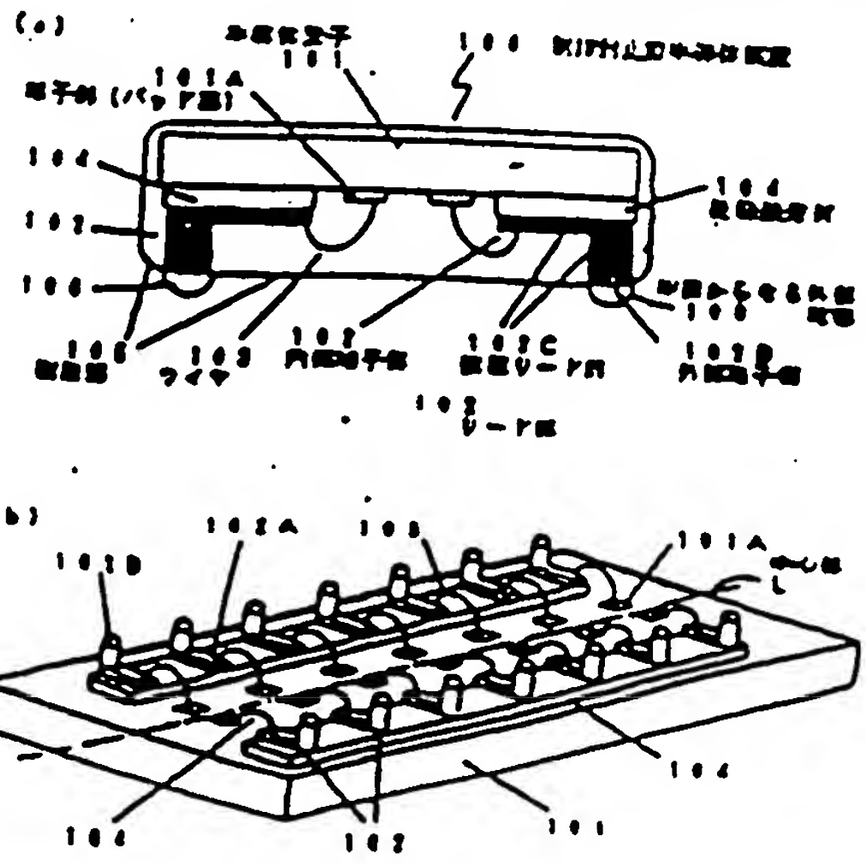
(54)【発明の名称】樹脂封止型半導体装置とそれに用いられるリードフレーム、及び樹脂封止型半導体装置の製造方法

(57)【要約】

【目的】 更なる樹脂封止型半導体装置の高密度化、高機能化が求められている中、本発明は実装パッケージフィズにおけるチップの占有率を上げ、半導体装置の小型化に対応させ、同時に従来のＴＳＯＰ等の小型パッケージに関連であった更なる多ピン化を実現した樹脂封止型半導体装置を提供する。

【構成】 半導体素子の端子側の面に、半導体素子の端子と電気的に接続するための内部端子部と、半導体素子の端子側の面へ反対して外部へと向く外部接続のための外部端子部と、前記内部端子部と外部端子部とを連続する接続リード部とを一体とした複数のリード部とを、絶縁接着材層を介して、接着して設けてあり、且つ、前記基板等への実装のための半田からなる外部電極を前記複数のリードの外部端子部に連結させ、少なくとも前記半田からなる外部電極の一部に樹脂部より外部に露出させて設けている。



{はかはスこと匹}

{はホ項1} 本よは主子の立子的の匹に ニよは主子の立子と元気的には対するための内部立子部と、本よは主子の立子前の匹へ立又して外部へと向く外部回路への接続のための外部立子部と、応記内部立子部と外部立子部とを連結する接続リード部とを一体としたリード部を有し、応記接続リード部を介して、比較してはけており、且つ、回路基板等への実装のための本田からなる外装樹脂を応記接続のをリードの外部立子部に達はさせ、少なくとも応記本田からなる外装樹脂の一部に本田部より外部に露出させてはけていることを特徴とする半導体装置。

{はホ項2} はホ項1において、本よは主子の立子は本よは主子の立子匹の一対の辺の中心線上にそって配置されており、リード部は対向の立子を挟むように対向し応記一対の辺にはいるけられていることを特徴とする樹脂封止型半よは体装置。

{はホ項3} 本よは主子の立子と元気的に接続するための内部立子部と、外部回路と接続するための外部立子部と、応記内部立子部と外部立子部とを連結する接続リード部とを一体とし、応外部立子部を、接続リード部を介して、リードフレーム面から直交する一方向に突出させ、対向し先端部同士で連結部を介して接続する一対の内部立子部を有並けており、且つ、る外部立子部の外側で、接続リード部と連結し、一体として全体を保持する外枠を立けていることを特徴とするリードフレー..

{はホ項4} 本よは主子の立子前の匹に、本よは主子の端子と元気的に接続するための内部立子部と、本よは主子の立子前の面へ直交して外部へと向く外部回路への接のための外部立子部と、応記内部立子部と外部立子とを連結する接続リード部とを一体とした有並のリー部とを、絶縁樹脂材料を介して、保持して立けてお..且つ、回路基板等への実装のための本田からなる外装樹脂を応記接続のをリードの外部立子部に達はさせ、なくとも応記本田からなる外装樹脂の一部は樹脂部より外部に露出させて立けている樹脂封止型半よは体装置の製方法であって、少なくとも、{A} エッチング加工て、半導体主子の端子と元気的に接続するための内部子部と、外部回路と接続するための外部端子部と、応記接続子部と外部は子部とを連結する接続リード部とを一体とし、応外部立子部を、接続リード部を介して、リードフレーム面から直交する一方向に突出させ、対向し先端部同士で連結部を介して接続する一対の内部立子部を有並けており、且つ、る外部端子部の外側で、接続リード部と連結し、一体として全体を保持する外枠を立けているリードフレームを作製する工程、{B} リードフレームの外部端子部以外の面（裏面）に樹脂を設け、打ちは全型により、対応する内部端子を接続する接続部と外部端子部に対応する位置に応にうれた接続リードを打ちは、リードフレームの外枠を打ちは、リードフレームの内部立子部と外部立子部とを連結する接続リード部を介して、リードフレーム立にとどまるように樹脂封止する工程、{C} リードフレームの外枠をるし不要の部分を打ちはきを型により切断除去する工程、{D} 本よは主子の立子部と、切断とりて、ニのは主子へ応じたした内部立子部の先端部とをワイヤボンディングしたはに、樹脂により応対主子部位のみを外気に露ニーマはを封止する工程、{E} 応記封止に露出した外部端子部位に本田からなる外装樹脂を付着する工程、とをることを特徴とする樹脂封止型本よは体のと方法。

{発明のお細な説明}

{0001}

{産業上の利用分野} 本発明は、本よは主子を収容する樹脂封止型の本よは実装（プラスチックパッケージ）に関し、特に、実装密度を向上させ、且つ、多ピン化に対応できる本よは体装置とその製造方法に関する。

{0002}

{従来の技術} 近年、半導体装置は、高集積化、小型化技術の進歩と二子機器の高性能化と携帯型小化の傾向（時代）から、ＬＳＩのＡＳＩＣに代表されるように、ますます高集積化、高機能化になってきている。これに従い、リードフレームを用いた封止型の半導体装置プラスチックパッケージにおいても、その発展のトレンドが、ＳＯＪ（Ｓｍａｌｌ Ｏｕｔｌｉｎｅ）－Ｌｅａｄｅｄ Ｐａｃｋａｇｅ）やＱＦＰ（Ｑｕａｄ Ｆｌａｔ Ｐａｃｋａｇｅ）のような実装実装型のパッケージを経て、ＴＳＯＰ（Ｔｉｎ Ｓｍａｌｌ Ｏｕｔｌｉｎｅ Ｐａｃｋａｇｅ）の発展による薄型化を主体としたパッケージの小型化へ、さらにはパッケージ内部の３次元化によるチップ収納効率向上を目的としたＬＯＣ（Ｌｅａｄ Ｏｎ Ｃｈｉｐ）の開発へと進展してきた。しかし、樹脂封止型半導体装置パッケージには、高集積化、高機能化とともに、更に一層の多ピン化、薄型化、小型化が求められており、上記最新のパッケージにおいてもチップ外周部分のリードの引き回しがあるため、パッケージの小型化に限界が見えてきた。また、ＴＳＯＰ等の小型パッケージにおいては、リードの引き回し、ピンピッチから多ピン化に対しても限界が見えてきた。

{0003}

{発明が解決しようとする課題} 上記のように、更なる樹脂封止型半導体装置の高集積化、高機能化が求められており、樹脂封止型半導体装置パッケージの一層の多ピン化、薄型化、小型化が求められている。本発明は、このような状況のもと、半導体装置パッケージサイズにおけるチップの占有率を上げ、半導体装置の小型化に対応でき、回路基板への実装信頼性を確保できる、即ち、回路基板への実装密度を向上させることができる樹脂封止型半導体装置を提供しようとするものである。また、従来

にQFP等の小型パッケージに収納されうる更なる多ピン化を実現しようとするものである．

【0004】

【課題を解決するための手段】本発明の樹脂封止型半導体装置は，半導体素子の電子制御面に，半導体素子の電子と電気的に接続するための内部端子部と，半導体素子の電子制御面へ垂立して外方へと向く外部回路への接続のための外部端子部と，前記内部端子部と外部端子部とを連結する段状リード部とを一体とした複数のリード部とを，絶縁接着層を介して，配置して設けており，且つ，回路基板等への実装のための半田からなる外部電極部を前記複数のリードの外部端子部に連結させ，少なくとも前記半田からなる外部電極部の一部は樹脂層より外部に露出させて設けていることを特徴とするものである．尚，上記において，内部端子部と外部端子部とを一体とした複数のリード部の配列を半導体素子の電子制御面上に二次元的に配列し，外部電極部を半田ボールにて形成することによりBCA（Ball Grid Array）タイプの樹脂封止型半導体装置とすることもできる．

【0005】そして，上記において，半導体素子の電子は半導体素子の電子面の一対の辺の中心線上にそって配置されており，リード部は複数の電子を挟むように対向し前記一対の辺に沿い設けられていることを特徴とするものである．また，本発明のリードフレームは，樹脂封止型半導体装置用のリードフレームであって，半導体素子の電子と電気的に接続するための内部端子部と，外部回路と接続するための外部端子部と，前記内部端子部と外部端子部とを連結する段状リード部とを一体とし，該外部端子部を，段状リード部を介して，リードフレーム面から垂立する一方向側に突出させ，対向し先端部同士で連結部を介して接続する一対の内部端子部を設け設けており，且つ，各外部端子部の外側で，段状リード部と連結し，一体として全体を保持する外枠部を設けていることを特徴とするものである．尚，上記リードフレームにおいて，内部端子部と外部端子部とそれを連結する段状リード部とを一体とした組みを複数リードフレーム部に二次元的に配列するして形成することによりBCA（Ball Grid Array）タイプの樹脂封止型半導体装置用のリードフレームとすることもできる．

【0006】本発明の樹脂封止型半導体装置の製造方法は，半導体素子の電子制御面に，半導体素子の電子と電気的に接続するための内部端子部と，半導体素子の電子制御面へ垂立して外部へと向く外部回路への接続のための外部端子部と，前記内部端子部と外部端子部とを連結する段状リード部とを一体とした複数のリード部とを，絶縁接着材層を介して，配置して設けており，且つ，回路基板等への実装のための半田からなる外部電極部を前記複数のリードの外部端子部に

半田からなる外部電極部の一部に樹脂封止型半導体装置の一部を形成している樹脂封止型半導体装置の製造方法であって，少なくとも，（A）エッチング加工にて，半導体素子の電子と電気的に接続するための内部端子部と，外部回路と接続するための外部端子部と，前記内部端子部と外部端子部とを連結する段状リード部とを一体とし，該外部端子部を，段状リード部を介して，リードフレーム面から垂立する一方向側に突出させ，対向し先端部同士で連結部を介して接続する一対の内部端子部を設けており，且つ，各外部端子部の外側で，段状リード部と連結し，一体として全体を保持する外枠部を設けているリードフレームを形成する工程，（B）前記リードフレームの外部端子部側でない面（裏面）に絶縁材を設け，打ち抜き金型により，対向する内部端子部同士を接続する連結部と該連結部に対応する位置に設けられた細みと打ち抜き，リードフレームの打ち抜かれた部分が半導体素子の電子にくるようにして，前記接着材を介して，リードフレーム全体を半導体素子へ固着する工程，（C）リードフレームの外枠部を含む不要の部分を打ち抜き金型により切断除去する工程，（D）半導体素子の電子と，切断されて，半導体素子へ固着された内部端子部の先端部とをワイヤボンディングした後に，樹脂により外部端子部底面のみを外部に露出させて全体を封止する工程，（E）前記外部に露出した外部端子部底面に半田からなる外部電極部を形成する工程，とを含むことを特徴とするものである．

【0007】

【作用】本発明の樹脂封止型半導体装置は，上記のような構成にすることにより，半導体装置パッケージサイズにおけるチップの占有率を上げ，半導体装置の小型化に対応できるものとしている．即ち，半導体装置の回路基板への実装面積を低減し，回路基板への実装密度の向上を可能としている．又しくは，内部端子部，外部端子部とを一体とした複数のリード部を半導体素子面に絶縁接着材層を介して固定し，前記外部端子部に半田からなる外部電極部を形成させていることより，装置の小型化を達成している．そして，上記半田からなる外部電極部を，半導体素子面に格子状な形で二次元的に配列することにより，半導体装置の多ピン化を可能としている．半田からなる外部電極部を半田ボールとし，二次元的には外部電極部を配列した場合にはBCAタイプとなり，半導体装置の多ピン化に対応できる．また，上記において，半導体素子の電子が半導体素子の電子面の一対の辺の中心線上にそって配置され，リード部に複数の電子を挟むように対向し前記一対の辺に沿い設けられており，簡単な構造とし，量産性に適した構造としている．本発明のリードフレームは，上記のような構成にすることにより，上記樹脂封止型半導体装置の製造を可能とするものであるが，従来のリードフレームと同様のエッチ

とができる．この結果，半導体素子搭載部上面と半導体素子の端子部にくるようにして，封止樹脂材を介して，リードフレーム全体を半導体素子へ接着し，リードフレームのタイバーを含む不要の部分をリード全面にメッキ処理することにより，内部端子と外部端子を一体としたものを多ピン半導体装置上に形成した．この結果，半導体装置の小型化が可能な，且つ，多ピン化が可能な樹脂封止型半導体装置の作製を可能としている．

【０００８】

【実施例】本発明の樹脂封止型半導体装置の実施例を以下，図にそって説明する．図１（ａ）は本実施例樹脂封止型半導体装置の断面図であり，図１（ｂ）に裏面の平面図である．図１中，１００は樹脂封止型半導体装置，１０１は半導体素子，１０２はリード部，１０２Ａは内部端子部，１０２Ｂは外部端子部，１０２Ｃは折曲リード部，１０１Ａは端子部（パッド部），１０３はワイヤ，１０４は絶縁接着材，１０５は接着部，１０６は半田（ペースト）からなる外部電極である．本実施例樹脂封止型半導体装置は，後述するリードフレームを用いたもので，内部端子部１０２Ａ，外部端子部１０２Ｂを一体としたし字型のリード部１０２を多ピン半導体素子１０１上に絶縁接着材１０４を介して接着し，且つ，外部端子部１０２Ｂ先に半田からなる外部電極を樹脂部１０５より外部へ突出させて設けた．パッケージ形状が半導体素子の形状に相似する樹脂封止型半導体装置である．回路基板へ搭載される際には，半田（ペースト）を溶解，固化して，外部端子部１０２Ｂが外部電極と電気的に接続される．本実施例樹脂封止型半導体装置は，図１（ｂ）に示すように，半導体素子１０１の端子部（パッド部）１０１Ａは半導体素子の中心線しにそって対向して２個づつ，中心線Ｌに対して配置されており，リード第１０２し，内部端子部１０２Ａが前記端子部（パッド部）に向った位置に半導体素子１０１の辺の外側に中心線を挟み対向するように配置されている．外部端子部１０２Ｂは内部端子部１０２Ａから折曲リード部１０２Ｃを介して離れて位置し，ほぼ半導体素子の側面上でに最った位置で半導体素子面に垂直する方向に，折曲リード１０２Ｃがし字に曲がり，外部端子部１０２Ｂはその先端に位置し，半導体素子の辺に平行な方向で一次元的に配列をしている．即ち，中心線しを挟み２列の外部端子部１０２Ｂの配列を設けている．そして，各外部端子に連結させ，半田（ペースト）からなる外部電極１０６を樹脂部１０５より外部に突出させて設けている．絶縁接着材１０４としては，１００μｍ厚のポリイミド系の熱可塑性樹脂であるＮＨＭ１２２Ｃ（日立化成工業社

製）を用いたが，他に，シリコン変性ポリイミドＴＡＩＩＩＳ（日立ヘークライト株式会社）や熱硬化型樹脂であるＨＣＳ２Ｃ０（三井三池化学株式会社製）等が挙げられる．上記実施例では，半田ペーストからなる外部電極であるが，この部分に半田ボールに代えてしまい．尚，本実施例樹脂封止型半導体装置は，上記のように，パッケージ形状が前記半導体素子の形状に相似する．極めて小型化されたパッケージであるが，取り方向についても，Ｍｉｎ．０ｍｍ以下にすることができ，実装し回路に占有できるものである．本実施例においては外部電極を，半導体素子の端子部（パッド部）に沿い２列に配列したが，半導体素子の端子の位置を二次元的に配置し，内部端子部と外部端子部との一体となった組みを任意．半導体素子の端子配列に二次元的に配列して形成することにより，半導体素子の，一層の多ピン化に十分対応できる．

【０００９】次いで，本発明のリードフレームの実施例を挙げ，図にもとづいて説明する．本実施例リードフレームは，上記実施例半導体装置に用いられたものである．図２に実施例リードフレームの平面図を示すもので，図２中，２００はリードフレーム，２０１は内部端子部，２０２は外部端子部，２０３は接続リード部，２０４は連結部，２０５は外枠部である．リードフレームは４２合金（Ｎｉ４２％のＦｅ合金）からなり，リードフレームの厚さは，内部端子部のある厚肉部で０．０５ｍｍ，外部端子部のある厚肉部で０．２ｍｍである．内部端子部の対向する先端部同士を連結する連結部２０５も薄肉（０．０５ｍｍ厚）に形成されており，後述する半導体装置を封止する際の打ち抜き金型にて打ち抜きし易い構造となっている．本実施例では外部端子部２０２は丸状であるが，これに限定はされない．また，リードフレーム材として４２合金を用いたがこれに限定されない．銅系合金でも良い．

【００１０】次に，上記実施例リードフレームの製造方法を図を用いて順に説明する．図４は本実施例リードフレームを製造した工程を示したものである．先ず，４２合金（Ｎｉ４２％のＦｅ合金）からなる，厚さ０．２ｍｍのリードフレーム素材３００を準備し，その両面を脱脂等を行いＡｒ逆スパッタした（図４（ａ））は，リードフレーム材料３００の両面に感光性のレジスト３０１を塗布し，乾燥した．（図３（ｂ））．

次いで，リードフレーム素材３００の両面から所定のパターン版を用いてレジストの所定の部分のみに露光を行った後，現像処理し，レジストパターン３０１Ａを形成した．（図３（ｃ））

尚レジストとしては東京応化株式会社製のネガ型感光性レジスト（ＰＭＥＲレジスト）を使用した．次いで，レジストパターン３０１Ａを耐腐食性膜として，５７°Ｃ，４８ボーメの塩化第二鉄水溶液にて，リードフレーム素材３００の両面からスプレイエッチングして，内部端

の工程図が図２に示されるリードフレームを作製した（図３（ｃ））．図２（ｂ）のに．図２のＡ－Ａ２における断面図である．これは．レジストを剥離した後．洗浄処理を施したは．所定の位置（外部端子部分をのぞく領域）のみに金メッキ処理を行った．（図３（ｅ））

尚．上記リードフレームの製造工程においては．図２（ｂ）に示すように．薄肉部と厚肉部を形成するため．外部端子形成面側からのエッチング（ＨＦ）を多く行い．反対面側からは少なのにエッチング（ＨＦ）を行った．また．金メッキに代え．銀メッキやパラジウムメッキでも良い．上記のリードフレームの製造方法は．１ケの半導体装置を作製するために必要なリードフレーム１ケの製造方法であるが．通常は生産性の面から．リードフレーム単位をエッチング加工する様．図２に示すリードフレームを複数個取りした状態で作製し．上記の工程を行う．この場合は．図２に示す外部端２０５の一部に連結するタイバー（図示していない）をリードフレームの外側に設けて連結状態とする．

【００１１】次に．上記のようにして作製されたリードフレームを用いた．本発明の樹脂封止型半導体装置の製造方法の実施例を図にそって説明する．図４は．本実施例樹脂封止型半導体装置の製造工程を示すものである．図３に示すようにして作製されたリードフレーム４００の外部端子部４０２先端部（斜面）と対向する裏面に．ポリイミド系熱硬化型の絶縁接着材（テープ）４０１（日立化成株式会社製．ＨＭ１２２Ｃ）を．４００°Ｃ．６Ｋｇ／ｍ²で１．０秒熱圧着してはりつけた（図４（ａ））．この状態の平面図を図５に示す．このはり合せは金型４０５Ａ．４０５Ｂにて（図４（ｂ））．対向する内部端子部の先端部を連結するタイバー４０３と．その部分の絶縁接着材（テープ）４０１とを打ち抜いた．（図４（ｃ））

次いで．外枠打ち抜および圧着用金型４０６Ａ．４０６Ｂを用い．外枠部４０４およびタイバーの部分を切り離す（図４（ｄ））と同時に．絶縁接着材４０４を介して半導体素子４０７上にリード部４０８の熱圧着を行った．（図４（ｅ））

尚．この図４（ｄ）に示す．外枠リードと連結してリードフレーム全体を支えている外枠２０４およびタイバーの部分を切り離しは．樹脂封止した後に行っても良い．この場合には．通常の多層リードフレームを用いたＱＦＰパッケージ等のようにダムバー（図示していない）を設けると良い．リード部４１０を半導体素子４１１へ搭載した後．ワイヤー４１４により．半導体素子のボンディングパッド４１１Ａとリード部４１０の内部端子４１０Ａとを電気的に接続した．（図４（ｆ））

その後．所定の金型を用い．エポキシ系の樹脂４１５でリード部４１０の外部端子部４１０Ｂのみを露出させて．全体を封止した．（図４（ｇ））

ここでは．専用の金型（図示していない）を用いた

所定の形（外部端子形）を得ることに．そして．しかも容易に必要としない．次いで．露出されている外部端子部４１０Ｂ上に半田ペーストをスクリーン印刷により塗布し．半田（ペースト）からなる外部端子４１６を作製し．本発明の樹脂封入型半導体装置を作製した．（図４（ｈ））

尚．半田からなる外部端子４１６の作製に．スクリーン印刷に限定されるものではなく．リフローまたはポッティング等でも．回路基板と半導体装置との接続に必要な量の半田が得られれば良い．

【００１２】

【発明の効果】本発明は．上記のように．新たな樹脂封止型半導体装置の製造方法．実装形態が定められる以前のもと．半導体装置パッケージサイズにおけるチップの占有率を上げ．半導体装置の小型化に対応させ．回路基板への実装面積を低減できる．即ち．回路基板への実装密度を向上させることができる半導体装置の提供を可能としたものであり．同時に従来のＴＳＯＰ等の小型パッケージに適用であった更なる多ピン化を実現した樹脂封止型半導体装置の提供を可能としたものである．

【図面の簡単な説明】

【図１】実施例の樹脂封入型半導体装置の製造装置図及び実装説明図

【図２】実施例のリードフレームの平面図

【図３】実施例のリードフレームの製造工程図

【図４】実施例の樹脂封止型半導体装置の製造工程図

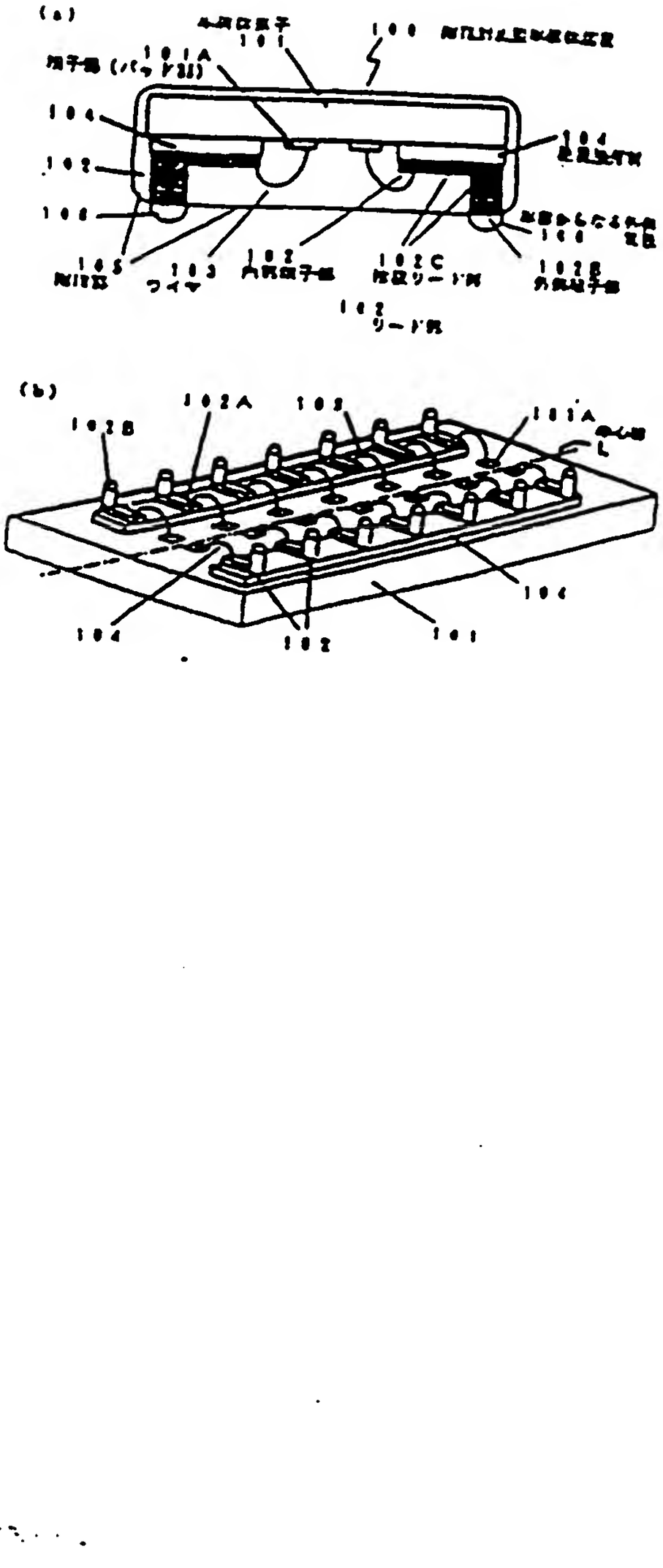
【図５】実施例のリードフレームに絶縁接着材をはりつけた状態の平面図

【符号の説明】

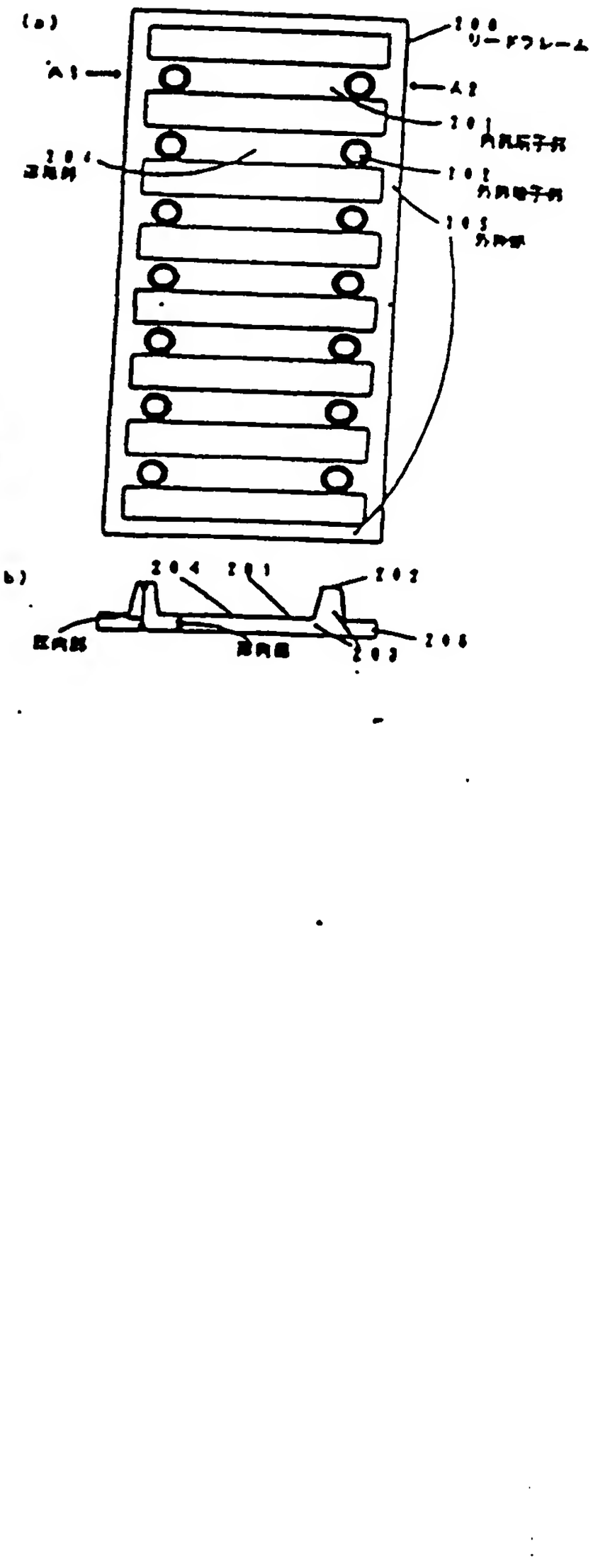
１００	樹脂封止型半導体装置
１０１	半導体素子
１０１Ａ	端子部（パッド部）
１０２	リード部
１０２Ａ	内部端子部
１０２Ｂ	外部端子部
１０２Ｃ	所定リード部
１０３	ワイヤ
１０４	絶縁接着材
１０５	樹脂部
１０６	半田（ペースト）からなる外部端子
２００	リードフレーム
２０１	内部端子部
２０２	外部端子部
２０３	所定リード部
２０４	連結部
２０５	外枠部
３００	リードフレーム素材
３０１	レジスト

303A	内部端子部
303B	外部端子部
304	連結部
305	金メッキ部
306	封止樹脂
400	リードフレーム
401	絶縁接着材（テープ）
402	外部端子部
403	連結部
405A、405B	打ち抜き穴
406A、406B	打ち抜きおよび位置決め穴
410	リード部
410A	内部端子部
410B	外部端子部
410C	接続リード部
411	半導体素子
411A	ワイヤー
415	吊り

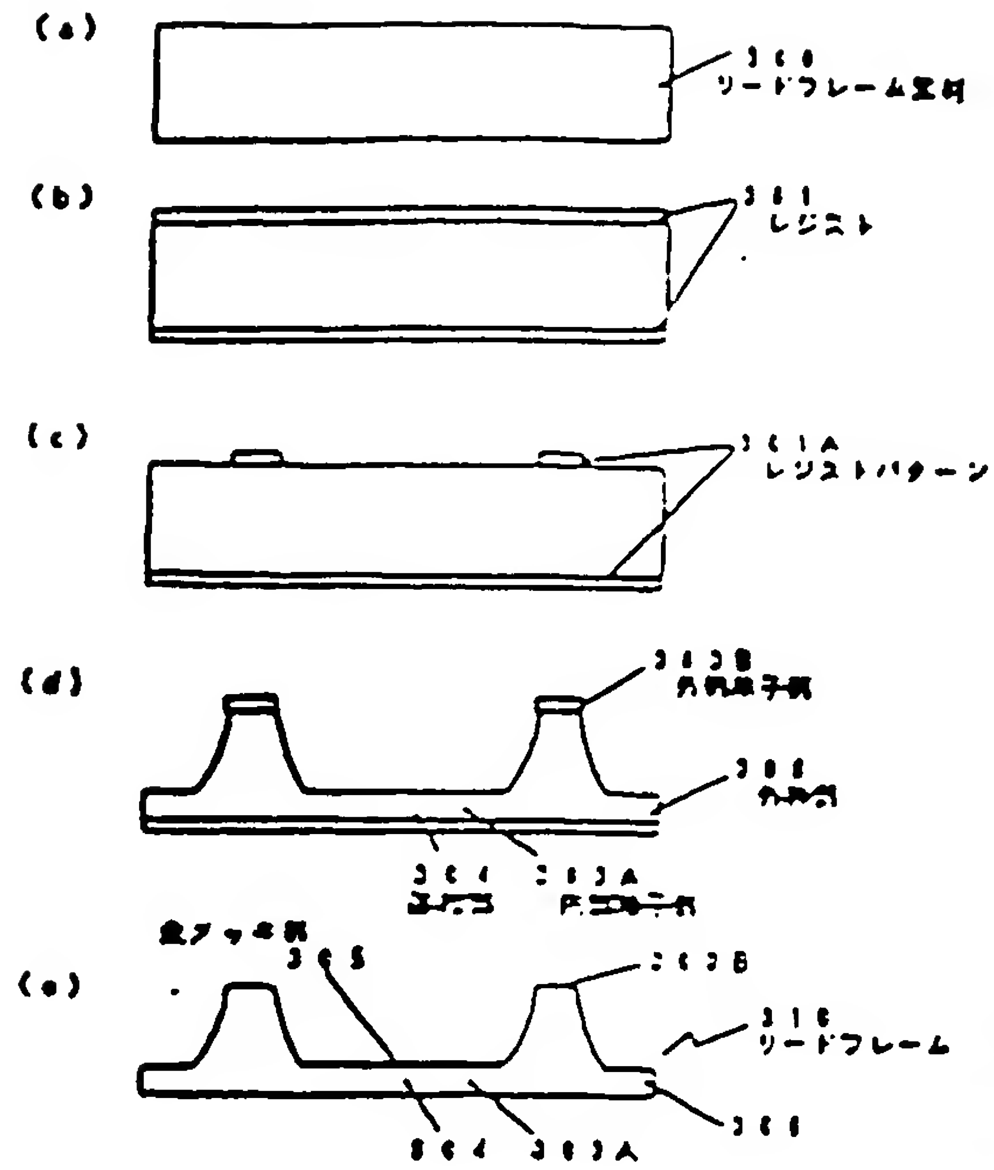
（図1）



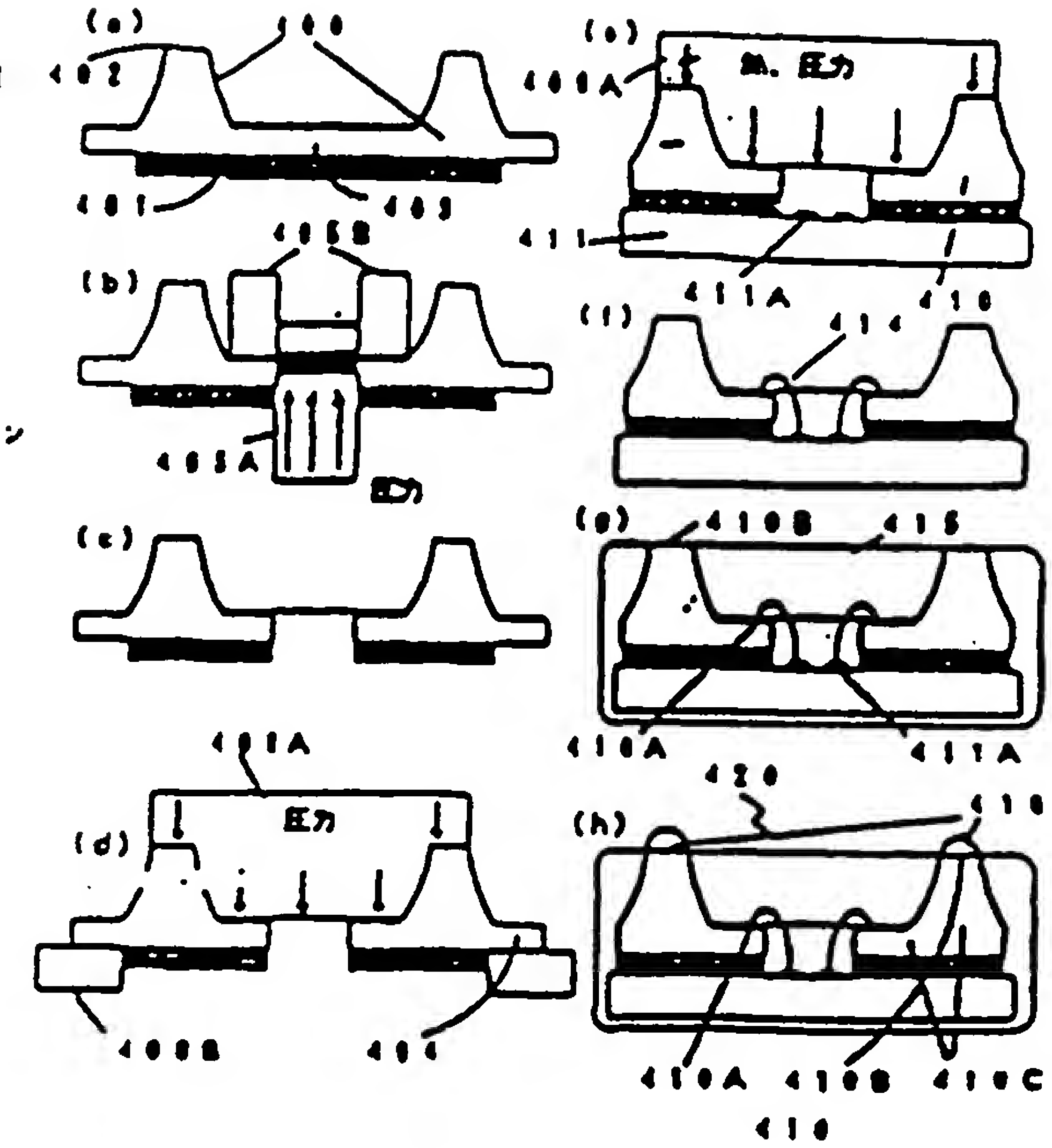
（図2）



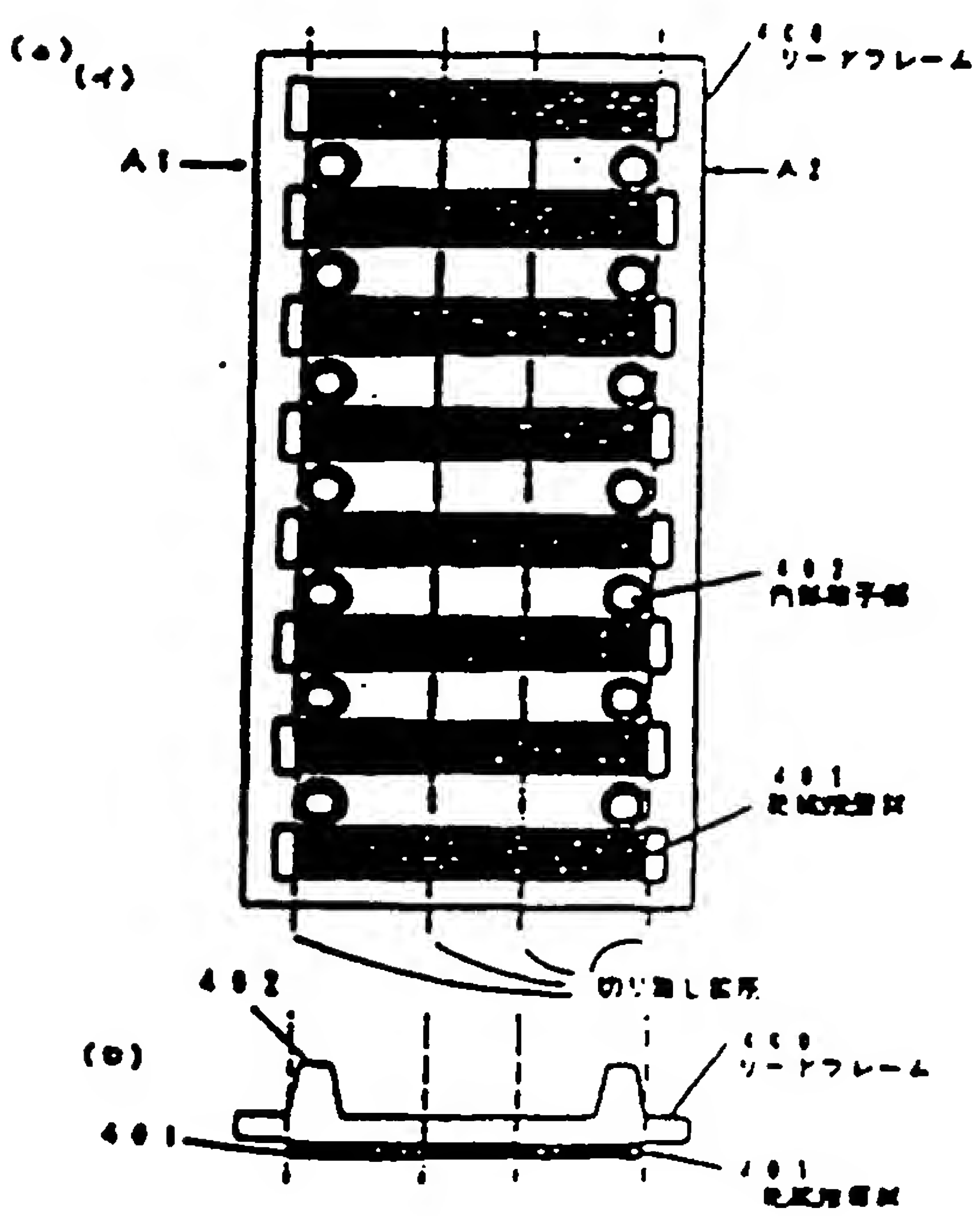
(図3)


(a)
リードフレーム素材
(b)
レジスト
(c)
レジストパターン
(d)
内部端子部
(e)
金メッキ部
リードフレーム

(図4)


(a)
(b)
(c)
(d)
圧力
(e)
熱、圧力
(f)
(g)
(h)

(図5)


(a)
A1
A2
リードフレーム
内部端子部
切り離し箇所
(b)

Japan se Patent Laid-Open Publication No. Heisei 8-125066

[TITLE OF THE INVENTION]

Resin Encapsulated Semiconductor Device, Lead Frame Used Therein, and Fabrication Method for the Resin Encapsulated Semiconductor Device

[CLAIMS]

1. A resin encapsulated semiconductor device comprising:

a semiconductor chip;

a plurality of leads fixedly attached to a terminal-end surface of the semiconductor chip by an insulating adhesive interposed between the semiconductor chip and the leads, each of the leads including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of the semiconductor chip, an outer terminal portion extending outwardly in a direction orthogonal to the terminal-end surface of the semiconductor chip and adapted to be connected to an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other; and

outer electrodes each connected to the outer terminal portion of an associated one of the leads and made of

solder to allow the semiconductor device to be mounted on a circuit board, at least a part of th outer leads being externally exposed from a resin encapsulat .

2. The resin encapsulated semiconductor device according to claim 1, wherein the terminals of the semiconductor chip are arranged along a substantially center line between a pair of sides of the semiconductor chip on the terminal-end surface of the semiconductor chip, and the leads are arranged in two facing sets along the sides of the semiconductor chip, respectively, in such a fashion that the terminals of the semiconductor chip are interposed between the two facing lead sets.

3. A lead frame comprising:

a plurality of leads each including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of a semiconductor chip, an outer terminal portion adapted to be connected to an associated one of terminals of an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other;

each of the outer terminal portions of the leads being protruded in a direction orthogonal to a lead frame

surface via an associated one of the connecting lead portions;

the inner lead portions of th leads being arranged in pair in such a fashion that the leads of each lead pair have facing tips, respectively;

connecting portions each adapted to connect the facing tips of the leads included in an associated one of the lead pairs; and

an outer frame portion arranged outside the outer terminal portions and connected to the connecting lead portions in such a fashion that they form an integral structure together, thereby protecting the entire portion of the lead frame.

4. A method for fabricating a semiconductor device including a semiconductor chip, a plurality of leads fixedly attached to a terminal-end surface of the semiconductor chip by an insulating adhesive interposed between the semiconductor chip and the leads, each of the leads including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of the semiconductor chip, an outer terminal portion extending outwardly in a direction orthogonal to the terminal-end surface of the semiconductor chip and adapted to be connected to an external circuit,

and a connecting lead portion adapted to connect the inner and outer terminal portions to each other; and outer electrodes each connected to the outer terminal portion of an associated one of the leads and made of solder to allow the semiconductor device to be mounted on a circuit board, at least a part of the outer leads being externally exposed from a resin encapsulate, comprising the steps of:

(A) fabricating a lead frame including a plurality of leads each including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of a semiconductor chip, an outer terminal portion adapted to be connected to an associated one of terminals of an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other, each of the outer terminal portions of the leads being protruded in a direction orthogonal to a lead frame surface via an associated one of the connecting lead portions, the inner lead portions of the leads being arranged in pair in such a fashion that the leads of each lead pair have facing tips, respectively, connecting portions each adapted to connect the facing tips of the leads included in an associated one of the lead pairs, and an outer frame portion arranged outside the outer terminal portions and connected to the connecting lead portions in such a fashion that they form

an integral structure together, thereby protecting the entire portion of the lead frame;

(B) applying an insulating layer to a surface of the lead frame opposite to the outer terminal portions, punching out the connecting portions adapted to connect facing ones of the inner lead portions to each other along with portions of the insulating layer respectively arranged at regions corresponding to the connecting portions by use of punching dies, aligning the punched portions of the lead frame with the terminals of the semiconductor chip, and mounting the entire portion of the lead frame on the semiconductor chip by the adhesive interposed therebetween;

(C) cutting off unnecessary portions of the lead frame including the outer frame portion by use of punching dies, thereby removing the cut-off portions;

(D) wire-bonding the terminals of the semiconductor chip with tips of the inner terminal portions mounted on the semiconductor chip, and encapsulating the semiconductor chip and the lead frame by a resin while allowing a surface of the lead frame toward the outer terminal portions to be externally exposed; and

(E) forming outer electrodes made of solder on the exposed lead frame surface toward the outer terminal portions.

[DETAILED DESCRIPTION OF THE INVENTION]

[FIELD OF THE INVENTION]

The present invention relates to a resin encapsulated semiconductor device (plastic package) in which a semiconductor chip is packaged, and more particularly to a semiconductor device configured to achieve an improvement in mounting density or to have a multi-pinned structure and a method for manufacturing such a semiconductor device.

[DESCRIPTION OF THE PRIOR ART]

Recently, semiconductor devices have been developed to have a higher integration degree and a higher performance by virtue of developments of techniques associated with an increase in integration degree and miniaturization and in pace with the tendency of electronic appliances to have a high performance and a light, thin, simple, and miniature structure. A representative example of such semiconductor devices is an ASIC of LSI. For instance, developments of resin encapsulated semiconductor device plastic packages have been advanced from surface-mounting packages such as SOJs (Small Outlined-Leaded Packages) or QFPs (Quad Flat Packages) to packages having a miniature structure mainly achieved in accordance with a thinness obtained by virtue of developments of TSOPs (Tin Small Outline Packages) or to LOC (Lead On Chip) structures

adapt d to achieve an improvement in the chip packaging efficiency by virtue of developments of an internal three-dimensional package structure. In addition to an increase in integration degree and improvement in performance, there has also been growing demand for an increase in the number of pins, thickness, and miniaturization of resin encapsulated semiconductor packages. In the above mentioned conventional packages, however, there is a limitation in miniaturization because those packages have a structure in which leads are arranged around a chip. Similarly, leads are arranged around a chip in the case of miniature packages such as TSOPs. In such packages, there is also a limitation in increasing the number of pins due to the pin pitch used.

[SUBJECT MATTERS TO BE SOLVED BY THE INVENTION]

As mentioned above, there has been demand for an increase in integration degree and improvement in performance of resin encapsulated semiconductor devices. Also, there has also been growing demand for an increase in the number of pins, thickness, and miniaturization of resin encapsulated semiconductor packages. In such situations, the present invention makes it possible to increase the occupancy degree of a chip in a semiconductor package with a limited size while reducing the mounting area of the

semiconductor package on a circuit board to achieve a miniaturization of the resulting semiconductor device. That is, the present invention is adapted to provide a resin encapsulated semiconductor device capable of achieving an improvement in the mounting density thereof on a circuit board. Also, the present invention is adapted to achieve an increase in the number of pins which is difficult in miniature packages such as conventional TSOPs.

[MEANS FOR SOLVING THE SUBJECT MATTERS]

The resin encapsulated semiconductor device of the present invention is characterized in that it comprises: a semiconductor chip; a plurality of leads fixedly attached to a terminal-end surface of the semiconductor chip by an insulating adhesive interposed between the semiconductor chip and the leads, each of the leads including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of the semiconductor chip, an outer terminal portion extending outwardly in a direction orthogonal to the terminal-end surface of the semiconductor chip and adapted to be connected to an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other; and outer electrodes each connected to the outer terminal portion of an associated one of the

leads and made of solder to allow the semiconductor device to be mounted on a circuit board, at least a part of the outer leads being externally exposed from a resin encapsulate. The above semiconductor device can be embodied into a BGA (Ball Grid Array) type resin encapsulated semiconductor device by arranging a plurality of leads each having an inner terminal portion and an outer terminal portion integral with each other in a two-dimensional fashion on the terminal-end surface of the semiconductor chip and forming the outer electrodes in the form of solder balls.

The above semiconductor device is also characterized in that the terminals of the semiconductor chip are arranged along a substantially center line between a pair of sides of the semiconductor chip on the terminal-end surface of the semiconductor chip, and the leads are arranged in two facing sets along the sides of the semiconductor chip, respectively, in such a fashion that the terminals of the semiconductor chip are interposed between the two facing lead sets. The lead frame of the present invention is characterized in that it comprises: a plurality of leads each including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of a semiconductor chip, an outer terminal portion adapted to be

connected to an associated one of terminals of an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other; each of the outer terminal portions of the leads being protruded in a direction orthogonal to a lead frame surface via an associated one of the connecting lead portions; the inner lead portions of the leads being arranged in pair in such a fashion that the leads of each lead pair have facing tips, respectively; connecting portions each adapted to connect the facing tips of the leads included in an associated one of the lead pairs; and an outer frame portion arranged outside the outer terminal portions and connected to the connecting lead portions in such a fashion that they form an integral structure together, thereby protecting the entire portion of the lead frame. The above lead frame can be embodied into a lead frame for a BGA (Ball Grid Array) type resin encapsulated semiconductor device by arranging a plurality of leads each having an inner terminal portion and an outer terminal portion integral with each other in a two-dimensional fashion on the terminal-end surface of the semiconductor chip and forming the outer electrodes in the form of solder balls.

The present invention is also characterized by a method for fabricating a semiconductor device including a semiconductor chip, a plurality of leads fixedly attached

to a terminal-end surface of the semiconductor chip by an insulating adhesive interposed between the semiconductor chip and the leads, each of the leads including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of the semiconductor chip, an outer terminal portion extending outwardly in a direction orthogonal to the terminal-end surface of the semiconductor chip and adapted to be connected to an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other; and outer electrodes each connected to the outer terminal portion of an associated one of the leads and made of solder to allow the semiconductor device to be mounted on a circuit board, at least a part of the outer leads being externally exposed from a resin encapsulate, comprising the steps of: (A) fabricating a lead frame including a plurality of leads each including integral portions, that is, an inner terminal portion adapted to be electrically connected to an associated one of terminals of a semiconductor chip, an outer terminal portion adapted to be connected to an associated one of terminals of an external circuit, and a connecting lead portion adapted to connect the inner and outer terminal portions to each other, each of the outer terminal portions of the leads being protruded in a direction orthogonal to a

lead frame surface via an associated one of the connecting lead portions, the inner lead portions of the leads being arranged in pair in such a fashion that the leads of each lead pair have facing tips, respectively, connecting portions each adapted to connect the facing tips of the leads included in an associated one of the lead pairs, and an outer frame portion arranged outside the outer terminal portions and connected to the connecting lead portions in such a fashion that they form an integral structure together, thereby protecting the entire portion of the lead frame; (B) applying an insulating layer to a surface of the lead frame opposite to the outer terminal portions, punching out the connecting portions adapted to connect facing ones of the inner lead portions to each other along with portions of the insulating layer respectively arranged at regions corresponding to the connecting portions by use of punching dies, aligning the punched portions of the lead frame with the terminals of the semiconductor chip, and mounting the entire portion of the lead frame on the semiconductor chip by the adhesive interposed therebetween; (C) cutting off unnecessary portions of the lead frame including the outer frame portion by use of punching dies, thereby removing the cut-off portions; (D) wire-bonding the terminals of the semiconductor chip with tips of the inner terminal portions mounted on the semiconductor chip, and

encapsulating the semiconductor chip and the lead frame by a resin while allowing a surface of the lead frame toward the outer terminal portions to be externally exposed; and

(E) forming outer electrodes made of solder on the exposed lead frame surface toward the outer terminal portions.

[FUNCTIONS]

With the above mentioned configuration, the resin encapsulated semiconductor device of the present invention can increase the occupancy degree of the chip while achieving a miniaturization thereof. That is, the resin encapsulated semiconductor device is capable of reducing the mounting area thereof on a circuit board and achieving an improvement in the mounting density thereof on the circuit board. In particular, the present invention achieves a miniaturization of the semiconductor device by fixedly attaching a plurality of leads each including an inner terminal portion and an outer terminal portion integral with each other to a surface of a semiconductor chip by an insulating adhesive layer interposed between the semiconductor chip and the leads, and connecting outer electrodes made of solder to the outer terminal portions, respectively. Also, the present invention achieves an increase in the number of pins in the semiconductor device by arranging the outer electrodes made of solder in a two-

dimensional fashion on a plane parallel to the surface of the semiconductor chip. Where the outer electrodes made of solder are formed in the form of solder balls and arranged in a two-dimensional fashion, a BGA type semiconductor device capable of achieving an increase in the number of pins can be obtained. In the above semiconductor device, the terminals of the semiconductor chip are arranged along a substantially center line between a pair of sides of the semiconductor chip on the terminal-end surface of the semiconductor chip, and the leads are arranged in two facing sets along the sides of the semiconductor chip, respectively, in such a fashion that the terminals of the semiconductor chip are interposed between the two facing lead sets. Thus, the semiconductor device has a simple structure suitable in regard to productivity. The lead frame of the present invention makes it possible to fabricate the above mentioned resin encapsulated semiconductor device by virtue of there above mentioned configuration thereof. However, this lead frame can be fabricated using a half etching method during an etching process as used for conventional lead frames. The method for fabricating a resin encapsulated semiconductor device in accordance with the present invention involves the steps of applying an insulating layer to a surface of the lead frame opposite to the outer terminal portions, punching out

the connecting portions adapted to connect facing ones of the inner lead portions to each other along with portions of the insulating layer respectively arranged at regions corresponding to the connecting portions by use of punching dies, aligning the punched portions of the lead frame with the terminals of the semiconductor chip, and mounting the entire portion of the lead frame on the semiconductor chip by the adhesive interposed therebetween, and cutting off unnecessary portions of the lead frame including the outer frame portion by use of punching dies, thereby removing the cut-off portions. Thus, a plurality of leads each including an inner terminal portion and an outer terminal portion integral with each other are mounted on a semiconductor chip. Accordingly, the present invention makes it possible to achieve a miniaturization of semiconductor devices. In accordance with the present invention, it is also possible to fabricate a resin encapsulated semiconductor device having an increased number of pins.

[EMBODIMENTS]

Hereinafter, embodiments of the present invention associated with resin encapsulated semiconductor devices will be described in conjunction with the annexed drawings. Fig. 1A is a cross-sectional view schematically

illustrating a resin encapsulated semiconductor device according to an embodiment of the present invention. Fig. 1B is a perspective view illustrating an essential part of the resin encapsulated semiconductor device. Figs. 1A and 1B, the reference numeral 100 denotes the resin encapsulated semiconductor device, 101 a semiconductor chip, 102 leads, 102A inner terminal portions, 102B outer terminal portions, 102C connecting lead portions, 101A contacts (pads), 103 wires, 104 an insulating adhesive, 105 a resin encapsulate, 106 outer electrodes made of solder (paste), respectively. The resin encapsulated semiconductor device according to this embodiment is fabricated using a lead frame which will be described hereinafter. In this resin encapsulated semiconductor device, a plurality of L-shaped leads 102, each of which has an inner terminal portion 102A and an outer terminal portion 102 integral with each other, are mounted on a semiconductor chip 101 by means of an insulating adhesive 104. An outer electrode 106, which is made of solder, is attached to each outer terminal portion 102B. The outer electrode 106 is outwardly protruded from a resin encapsulate 105. The resin encapsulated semiconductor device configured as mentioned above has a package area substantially equal to the entire area thereof. When this semiconductor device is mounted on a circuit board, the

solder is melted and then solidified to allow the outer terminal portions 102B to be electrically connected to an external circuit. In the resin encapsulated semiconductor device according to the illustrated embodiment, contacts (pads) 101A provided at the semiconductor chip 101 are arranged in pairs along a center line L of the semiconductor chip 101 at opposite sides of the center line L in such a fashion that contacts included in each contact pair face each other. The outer terminal portion 102B of each lead is spaced apart from the inner terminal portion 102A of the lead. Between the inner and outer terminal portions 102A and 102B, a connecting lead portion 102C is interposed. The connecting lead portion 102C of each lead is bent in a direction orthogonal to the major surface of the semiconductor chip at a position near an associated one of the side surfaces of the semiconductor chip 101, so that it has an L shape. In each lead, the outer terminal portion 102B is arranged at an end of the connecting lead portion 102C. The outer terminal portions 102B of the leads are arranged in a one-dimensional fashion on a plane parallel to the major surface of the semiconductor chip 101. That is, the outer terminal portions 102B are arranged in two lines at opposite sides of the center line L. As mentioned above, one outer electrode 106 made of solder is connected to the outer terminal portion 102B of

each lead and outwardly exposed from the resin encapsulate 105.

For the insulating adhesive 104, a polyimide-based thermoplastic adhesive having a thickness of 100 μm (HM122C manufactured by Hitachi Chemical Co., Ltd.) is preferably used. Alternatively, a silicon denaturalized polyimide adhesive (ITA1715 manufactured by Sumitomo Bakelite Co., Ltd.) or a thermosetting adhesive (HG5200 manufactured by Tomoekawa Papermaking Co., Ltd.) may be used. Although outer electrodes made of solder paste are used in the illustrated embodiment, solder balls may be used.

As mentioned above, the resin encapsulated semiconductor device according to the illustrated embodiment has a package area substantially equal to the entire area thereof. That is, the illustrated embodiment of the present invention provides a package having a compact structure in regard to area. In accordance with the present invention, a thinned package structure can also be provided in that it is also possible to reduce the package thickness to about 1.0 mm or less. Although the outer electrodes have been described as being arranged in two lines along the contacts (pads) of the semiconductor chip, they may be arranged in a two-dimensional fashion. This is achieved by arranging contacts of the semiconductor chip in a two-dimensional fashion. On the surface of the

semiconductor chip arranged with those contacts, a plurality of terminal sets each having an inner terminal and outer terminal integral with each other are arranged in a two-dimensional fashion. In this case, it is possible to fabricate a semiconductor device using a semiconductor chip with an increased number of pins.

An embodiment of the present invention associated with a lead frame will now be described. The lead frame according to this embodiment is adapted to be used in the above mentioned semiconductor device. Fig. 2 is a plan view of the lead frame according to this embodiment. In Fig. 2, the reference numeral 200 denotes a lead frame, 201 inner terminal portions, 202 outer terminal portions, 203 connecting lead portions, 204 a connecting portion, and 205 an outer frame portion, respectively. The lead frame is made of 42 ALLOY (namely, an Fe alloy containing 42% Ni). The lead frame has a thickness of 0.05 mm at its thinner portion, that is, the inner terminal portions, and a thickness of 0.2 mm at its thicker portion, that is, the outer terminal portions. The connecting portion, which connects facing tips of the inner terminal portions to each other, has a thickness of 0.05 mm corresponding to that of the thinner portion. This connecting portion has a structure capable of allowing an easy punching thereof in the fabrication of the semiconductor device, as described

hereinafter. Although the outer terminal portions 202 have a ball shape in the illustrated embodiment, they are not limited to this shape. Also, although the lead frame has been described as being made of the 42 ALLOY, it is not limited to this material. For the lead frame, a copper-based alloy may be used.

Now, fabrication of the lead frame according to the illustrated embodiment will be described in brief. Fig. 4 illustrates a process for fabricating the lead frame according to the illustrated embodiment. First, a lead frame blank 300 having a thickness of 0.2 mm was prepared which is made of a 42 ALLOY (an Fe alloy containing 42% Ni). The prepared lead frame blank 300 was then subjected to a cleaning process, thereby removing grease from the surfaces thereof (Fig. 3a). Subsequently, photoresist films 301 were coated over both surfaces of the lead frame blank 300, respectively. The coated photoresist films 301 were then dried (Fig. 3b).

Using desired pattern plates, the photoresist films 301 on both surfaces of the lead frame blank 300 were exposed to light at their desired portions. A developing process was then conducted to the light-exposed photoresist films 301, thereby forming photoresist patterns 301A.

For the photoreist films, a negative liquid-phase resist (PMER resist) manufactured by Tokyo Ohka Co., Ltd.

was used. Using the resist patterns 301A as anti-etch films, the lead frame blank 300 was subjected to a spray etching process at both surfaces thereof. The spray etching process was conducted using a ferric chloride solution of 48 BAUME at 57 °C. Thus, a lead frame having a structure of Fig. 2a was obtained (Fig. 3d). Fig. 2a is a plan view of the lead frame. Fig. 2b is a cross-sectional view taken along the line A1 - A2 of Fig. 2a. Thereafter, the remaining photoresist thin films were peeled off. The resulting structure was then subjected to a cleaning process. A gold plating process was subsequently conducted for desired portions of the lead frame, that is, regions including inner terminal portions (Fig. 3e).

In the fabrication process of the lead frame, the etching process was conducted with a large etch depth at one major surface of the lead frame blank where outer terminal portions are to be formed, and with a small etch depth at the other major surface of the lead frame. In place of the gold plating, silver or palladium plating may be utilized. The above mentioned lead frame fabrication process is adapted to manufacture a single lead frame required for the manufacture of a single semiconductor device. In terms of productivity, however, the etching process is conducted for lead frame units each corresponding to the single lead frame shown in Fig. 2. To

this end, a frame member (not shown) is provided at a desired portion of the peripheral edge of the lead frame so as to connect a desired part of the outer frame portion 205 shown in Fig. 2 to a corresponding one of an adjacent lead frame.

Using the lead frame fabricated as mentioned above, the resin encapsulated semiconductor device according to the present invention was fabricated. Now, a method for fabricating the resin encapsulated semiconductor device in accordance with an embodiment of the present invention will be described. Fig. 4 illustrates the method for fabricating the resin encapsulated semiconductor device in accordance with the embodiment of the present invention. A polyimide-based thermosetting insulating adhesive (tape) 401 (HM122C manufactured by Hitachi Chemical Co., Ltd.) was applied to one surface, formed with the outer terminal portions 402, of the lead frame 400 fabricated as in Fig. 3 and the outer surface of the lead frame 400 using a hot pressing process conducted at 400 °C and 6 Kg/m^2 for 1.0 second Fig. 4a). The resulting structure is shown in Fig. 5 which is a plan view. Thereafter, the connecting portions 403 connecting facing tips of the inner terminal portions were punched using punching dies 405A and 405B (Fig. 4b). Also, portions of the insulating adhesive

(tape) corresponding to thos connecting portions 403 were punched (Fig. 4c)

Subsequently, unnecessary portions of the lead frame including the outer frame 404 were cut off using outer frame punching and pressing dies 406A and 406B (Fig. 4d). The lead frame was then bonded to a semiconductor chip 407 at its leads 410 under pressure while applying heat (Fig. 4e).

The process for cutting off the unnecessary portion of the lead frame including the outer frame 404 supporting the entire portion of the lead frame along with the connecting lead portion, as shown in Fig. 4d, may be carried out after an resin encapsulating process. In this case, dam bars (not shown) are preferably provided, as in QFP packages typically using a lead frame having a single layer structure. After the mounting of the leads 410 on the semiconductor chip 411, the inner terminal portion 410 of each lead 410 was electrically connected to an associated one of terminals (pads) 411A of the semiconductor chip 411 (Fig. 4f).

Subsequently, an epoxy-based resin 415 was molded to encapsulate the resulting structure while exposing the outer terminal portions 410B of the leads 410 using a desired mold (Fig. 4g).

Although a specific mold (not shown) was used for the above process in the illustrated case, use of such a die may be unnecessary in so far as th resin encapsulating process can be conducted under the condition in which desired portions (outer terminal portions) of the lead frame are left. Thereafter, a solder paste was coated on the exposed outer terminal portions 410B in accordance with a screen printing process, thereby forming outer electrodes 416 made of solder (paste). Thus, the fabrication of the resin encapsulated semiconductor device according to the present invention was achieved (Fig. 4h).

Although the formation of the outer electrodes 416 made of solder has been described as being achieved using a screen printing process, it may be achieved using a reflow or bonding process in so far as an amount of solder required for a connection of the semiconductor device to a circuit board is obtained.

[EFFECTS OF THE INVENTION]

As apparent from the above description, the present invention makes it possible to increase the occupancy degree of a semiconductor chip in a semiconductor package in situations requiring new resin encapsulated semiconductor devices having a highly integrated structure while exhibiting a high performance. The present invention

also makes it possible to reduce the area of the semiconductor devic on a circuit board in order to cope with a compactness of the semiconductor d vic . That is, the present invention can provide a semiconductor device capable of achieving an improvement in the mounting density on a circuit board. At the same time, the present invention can provide a resin encapsulated semiconductor device having a new multipinned structure which could not be realized in compact packages such as conventional TSOPs.